

STF16NK60Z STP16NK60Z, STW16NK60Z

N-channel 600 V, 038 Ω, 14 A, TO-220, TO-220FP, TO-247 Zener-protected SuperMESH[™] Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)} max	I _D	Pw
STF16NK60Z	600 V	< 0.42 Ω	14 A ⁽¹⁾	40 W
STP16NK60Z	600 V	< 0.42 Ω	14 A	190 W
STW16NK60Z	600 V	< 0.42 Ω	14 A	190 W

1. Limited by package.

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability

Application

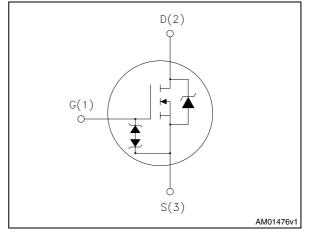
Switching applications

Description

The new SuperMESH[™] series of Power MOSFETS is the result of further design improvements on ST's well-established stripbased PowerMESH[™] layout. In addition to significantly lower on-resistance, the device offers superior dv/dt capability to ensure optimal performance even in the most demanding applications. The SuperMESH[™] devices further complement an already broad range of innovative high voltage MOSFETs, which includes the revolutionary MDmesh[™] products.

	3
TO-220FP ¹	TO-220
	TO-247

Figure 1. Internal schematic diagram



Order codes	Marking	Package	Packaging
STF16NK60Z	F16NK60Z	TO-220FP	
STP16NK60Z	P16NK60Z	TO-220	Tube
STW16NK60Z	W16NK60Z	TO-247	

Doc ID 10249 Rev 5

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Electrical ratings 1

Deveryotev	Value	11	
Parameter	TO-220 / TO-247	TO-220FP	Unit
Drain-source voltage ($V_{GS} = 0$)	600		V
Gate- source voltage	± 30		V
Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	14	14 ⁽¹⁾	А
Drain current (continuous) at $T_C = 100 \ ^{\circ}C$	8.8	8.8 ⁽¹⁾	А
Drain current (pulsed)	56	56 ⁽¹⁾	А
Total dissipation at $T_C = 25 \text{ °C}$	190	40	W
Derating factor	1.51		W/°C
Gate source ESD(HBM-C = 100 pF, R = 1.5 k Ω)	6000		V
Peak diode recovery voltage slope	4.5		V/ns
Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; Tc = 25 °C)	2500		V
Storage temperature	-55 to 150		°C
Max. operating junction temperature	150		°C
	Gate- source voltageDrain current (continuous) at $T_C = 25$ °CDrain current (continuous) at $T_C = 100$ °CDrain current (pulsed)Total dissipation at $T_C = 25$ °CDerating factorGate source ESD(HBM-C = 100 pF, R = 1.5 k\Omega)Peak diode recovery voltage slopeInsulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; Tc = 25 °C)Storage temperature	ParameterTO-220 / TO-247Drain-source voltage ($V_{GS} = 0$)600Gate- source voltage ± 30 Drain current (continuous) at $T_C = 25 \ ^{\circ}C$ 14Drain current (continuous) at $T_C = 100 \ ^{\circ}C$ 8.8Drain current (pulsed)56Total dissipation at $T_C = 25 \ ^{\circ}C$ 190Derating factor1.51Gate source ESD(HBM-C = 100 pF, R = 1.5 k Ω)6000Peak diode recovery voltage slope4.5Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; Tc = 25 \ ^{\circ}C)55 to 150Storage temperature-55 to 150	Parameter TO-220 / TO-247 TO-220FP Drain-source voltage (V _{GS} = 0) 600 Gate- source voltage \pm 30 Drain current (continuous) at T _C = 25 °C 14 14 ⁽¹⁾ Drain current (continuous) at T _C = 100 °C 8.8 8.8 ⁽¹⁾ Drain current (pulsed) 56 56 ⁽¹⁾ Total dissipation at T _C = 25 °C 190 40 Derating factor 1.51 56 Gate source ESD(HBM-C = 100 pF, R = 1.5 k\Omega) 6000 6000 Peak diode recovery voltage slope 4.5 2500 Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; Tc = 25 °C) 2500 2500 Storage temperature -55 to 15- 2500 2500

Table 2 Absolute maximum ratings

1. Limited by package

2. Pulse width limited by safe operating area

3. I_{SD} $\ \leq \$ 14 A, di/dt $\ \leq \$ 200 A/µs, V_{DD} = 80% V_(BR)DSS

Table 3. Thermal data

Symbol	Parameter TO-220 TO-24		TO-247	TO-220FP	Unit
R _{thj-case}	Thermal resistance junction-case max	0.66 3.1		°C/W	
R _{thj-amb}	Thermal resistance junction-ambient max	62.5	50	62.5	
ТI	Maximum lead temperature for soldering purpose	300		°C	

Table 4. **Avalanche characteristics**

Symbol	Parameter	Max value	Unit
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_j max)	14	A
E _{AS}	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}, I_D = I_{AR}, V_{DD} = 50 \text{ V}$)	360	mJ



2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{D} = 1 \text{ mA}, V_{GS} = 0$	620			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = Max rating V _{DS} = Max rating, T _C =125 °C			1 50	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			± 10	μA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 50 \ \mu A$	3	3.75	4.5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 7 A		0.38	0.42	Ω

Table 5. On /off states

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0	-	2650 285 62	-	pF pF pF
C _{OSS eq} ⁽¹⁾	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0$ to 480 V	-	158	-	pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} = 480 V, I _D = 14 A, V _{GS} = 10 V (see <i>Figure 19</i>)	-	86 17 46	-	nC nC nC

1. $C_{oss\;eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_DS increases from 0 to 80% V_{DSS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off-delay time Fall time	$V_{DD} = 480 \text{ V}, I_D = 14 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 18</i>)	-	30 25 70 15	-	ns ns ns ns



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		-		14 56	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 14 A, V _{GS} = 0	-		1.6	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 14 A, di/dt = 100 A/μs V _{DD} = 100 V (see <i>Figure 23</i>)	-	490 5.4 22		ns nC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 14 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$ $V_{DD} = 100 \text{ V}, \text{ T}_{j} = 150 ^{\circ}\text{C}$ (see <i>Figure 23</i>)	-	585 7 24		ns nC A

Table 8.Source drain diode

1. Pulse width limited by safe operating area

2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%

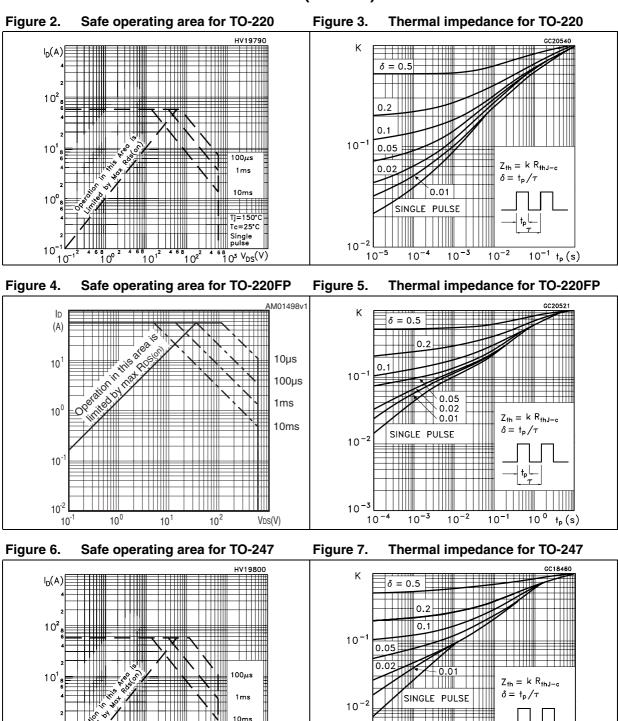
Table 9. Gate-source Zener of	diode
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Symbol	Parameter	Test conditions	Min	Тур	Max	Unit
BV _{GSO}	Gate-source breakdown voltage	lgs=± 1 mA (open drain)	30	-	-	V

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.



2.1 Electrical characteristics (curves)



 10^{-3}

10⁻⁵

10-4

 10^{-3}

 10^{-2}

 $10^{-1} t_{p}(s)$

Tj=150°C Tc=25°C Single pulse

103 V_{DS}(V)

4 6

10²²

10¹²

4 6



10

10

10

1°1

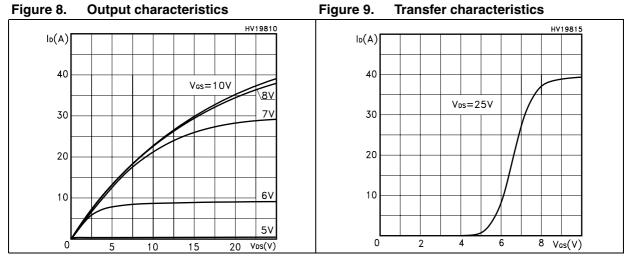


Figure 10. Normalized BV_{DSS} vs temperature Figure 11. Static drain-source on resistance

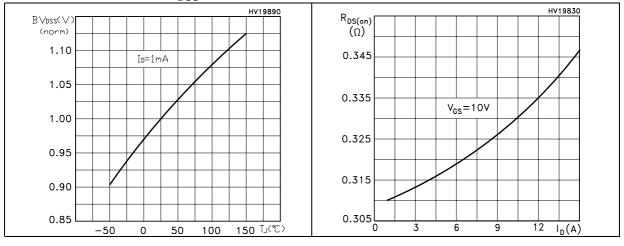
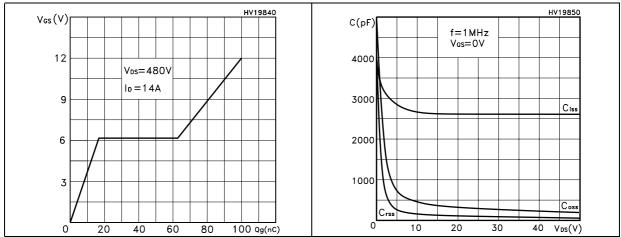


Figure 12. Gate charge vs gate-source voltage Figure 13. Capacitance variations



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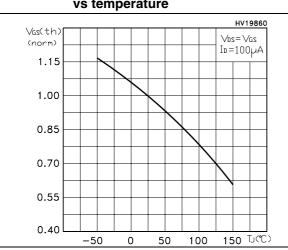
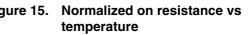


Figure 14. Normalized gate threshold voltage Figure 15. vs temperature



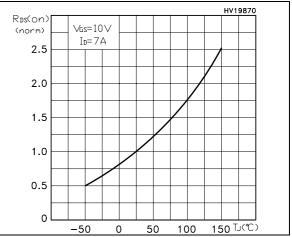
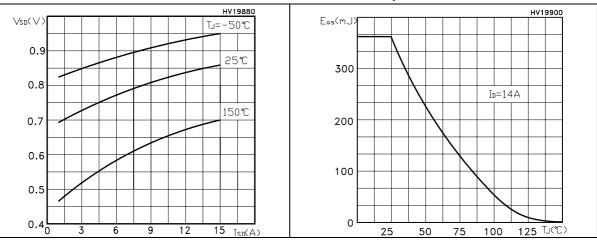


Figure 16. Source-drain diode forward characteristics

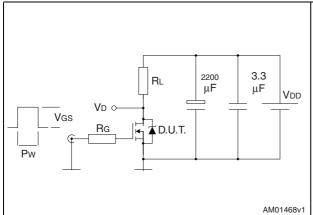
Figure 17. Maximum avalanche energy vs temperature





3 Test circuits

Figure 18. Switching times test circuit for resistive load



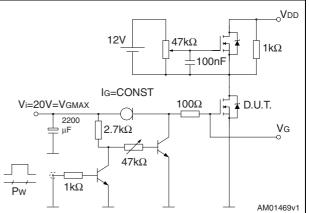
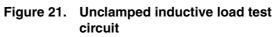


Figure 20. Test circuit for inductive load switching and diode recovery times



I

JJJJ

2200

μF

3.3

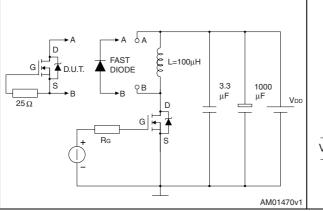
μF

Vdd

VD O

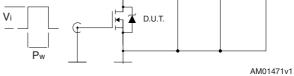
lр

0

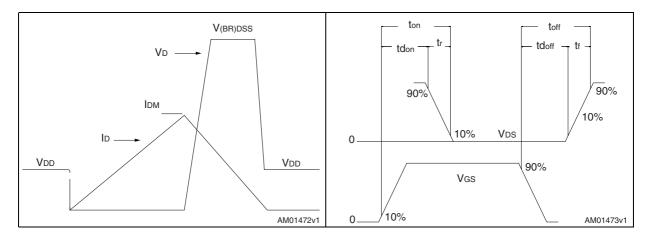


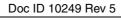


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4 Package mechanical data

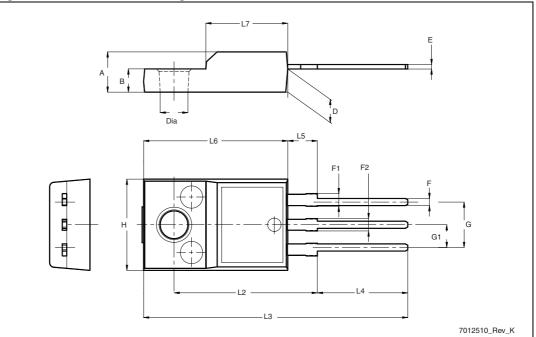
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.



Dim	mm				
	Min.	Тур.	Max.		
А	4.4		4.6		
В	2.5		2.7		
D	2.5		2.75		
E	0.45		0.7		
F	0.75		1		
F1	1.15		1.70		
F2	1.15		1.70		
G	4.95		5.2		
G1	2.4		2.7		
Н	10		10.4		
L2		16			
L3	28.6		30.6		
L4	9.8		10.6		
L5	2.9		3.6		
L6	15.9		16.4		
L7	9		9.3		
Dia	3		3.2		

Table 10. TO-220FP mechanical data

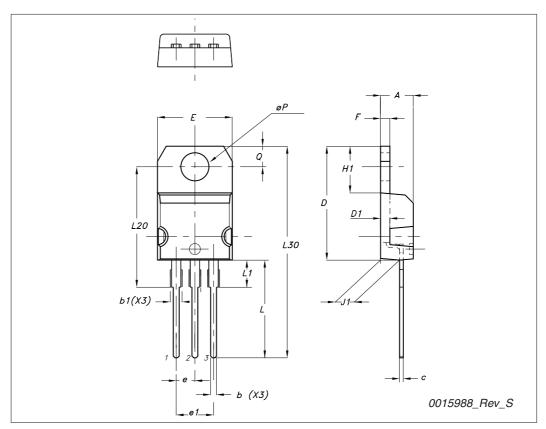
Figure 24. TO-220FP drawing





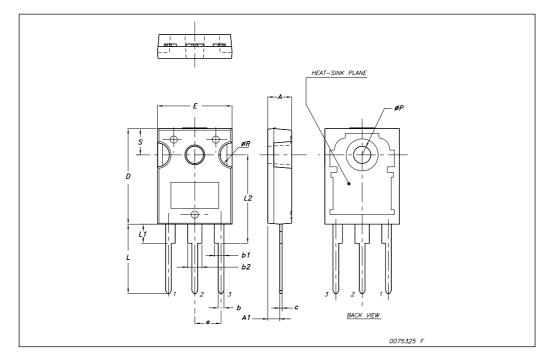
Dim	mm			
	Min	Тур	Max	
Α	4.40		4.60	
b	0.61		0.88	
b1	1.14		1.70	
С	0.48		0.70	
D	15.25		15.75	
D1		1.27		
E	10		10.40	
е	2.40		2.70	
e1	4.95		5.15	
F	1.23		1.32	
H1	6.20		6.60	
J1	2.40		2.72	
L	13		14	
L1	3.50		3.93	
L20		16.40		
L30		28.90		
ØP	3.75		3.85	
Q	2.65		2.95	







	TO-247 Mechanical data		
Dim.		mm.	
	Min.	Тур	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
Е	15.45		15.75
е		5.45	
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
øP	3.55		3.65
øR	4.50		5.50
S		5.50	





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5 Revision history

Table 11.Document revision history

Date	Revision	Changes
11-Sep-2006	3	
07-Jun-2007	4	Added statement for ECOPACK [®] .
04-Dec-2009	5	Updated packages mechanical data.



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